

Notic of R ferences Cit d	Application/Control No. 10/656,377	Applicant(s)/Patent Under Reexamination SAKURAI ET AL.	
	Examiner Hoan H. Tran	Art Unit 2852	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,144,812	11-2000	Ueno, Fumihito	399/12
	B	US-6,253,035	06-2001	Kawana et al.	399/24
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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